Workshop



Paving the Way for Seamless Characterization, Simulation and Development

Second Workshop of the MessLeha Project

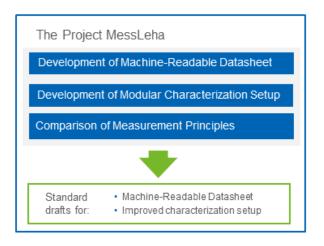
The project MessLeha analyses measurement methods and environments for the characterization of fast switching power semiconductors and develops a digital datasheet suitable for all simulation tools. The results will be included in two standardization drafts for the International Electrotechnical Commission IEC. These drafts will address the currently limited application of established characterization standards for fast switching semiconductors, improve traceability of measurements, and enable easy parametrization for simulation models.

We invite you to our second workshop on

23 September 2021, 14:00 - 18:00 (CEST).

The workshop will feature presentations of

- how the feedback from the first workshop was implemented,
- the demonstrators for the machine-readable datasheet and the measurement setup for the Double-Pulse Test,
- further measurement methods for future application.



Registration and Information

The workshop is aimed at users and developers of power electronic systems and manufacturers of power semiconductor and simulation tools.

Register <u>here</u> until **16 September 2021**. The workshop is free of charge.

Venue: VUV Akademie, Stresemannallee 30, 60596 Frankfurt am Main / Germany (hybrid or online event depending on the COVID-19 situation)

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For more information on the project, visit the <u>project website</u>.







Agenda

23 September 2021, Hybrid Workshop	
14:00 – 14:10	Welcome and Introduction Alexandra Fabricius, VDE DKE
14:10 – 14:30	MessLeha: Project Motivation and Goals Kevin Hermanns, PE-Systems GmbH Uwe Jansen, Infineon Technologies AG
14:30 – 14:40	Summary of the 1st Workshop and Participants' Feedback Jens Schweickhardt, PE-Systems GmbH
14:40 –15:30	Proposal for a Versatile High Power Double Pulse Test Setup Uwe Jansen, Infineon Technologies AG Vishal Jadhav, Infineon Technologies AG Hui Bo Sun, Infineon Integrated Circuit (Beijing) Co., Ltd.
15:30 – 16:00	Coffee Break
16:00 – 16:50	Machine-readable Data Sheets: Provision and Application Philipp Kappes, PE-Systems GmbH
16:50 – 17:25	Switching Loss Measurement Methods for the Future Ying Su, PTB Physikalisch Technische Bundesanstalt Julian Weimer, University of Stuttgart
17:25 – 17:50	Workshop Summary MessLeha Partners
17:50 – 18:00	Next Steps and Closing Remarks Alexandra Fabricius, VDE DKE